

Notice of References Cited	Application/Control No. 10/559,864		Applicant(s)/Patent Under Reexamination HAIK-BERAUD ET AL.	
	Examiner Ngoc-Yen M. Nguyen		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-3,977,843	08-1976	Dew et al.	48/197R
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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